

AUTOMOTIVE CURRENT TRANSDUCER OPEN LOOP TECHNOLOGY HC5FW 600-S/SP1





Introduction

The HC5FW family is for the electronic measurement of DC, AC or pulsed currents in high power and low voltage automotive applications with galvanic separation between the primary circuit (high power) and the secondary circuit (electronic circuit).

The HC5FW family gives you the choice of having different current measuring ranges in the same housing.

Features

- Open Loop transducer using the Hall effect
- Low voltage application
- Unipolar + 5 V DC power supply
- Primary current measuring range up to ± 600 A
- Maximum RMS primary current limited by the busbar, the magnetic core or the ASIC temperature T° < + 150 °C
- Operating temperature range: 40 °C < T° < + 125 °C
- Output voltage: full ratiometric (sensitivity and offset)
- High speed transducer.

Special feature

Cover without sleeve (reduced insulation).

Advantages

- Good accuracy
- Good linearity
- Low thermal offset drift
- Low thermal sensitivity drift.

Automotive applications

- Electrical Power Steering
- Starter Generators
- Converters.



The open loop transducers use a Hall effect integrated circuit. The magnetic flux density *B*, contributing to the rise of the Hall voltage, is generated by the primary current I_P to be measured. The current to be measured I_P is supplied by a current source i.e. battery or generator (Figure 1).

Within the linear region of the hysteresis cycle, *B* is proportional to:

$$B(I_{\rm P})$$
 = constant (a) x $I_{\rm P}$

The Hall voltage is thus expressed by:

 $V_{\rm H}$ = ($R_{\rm H}$ /d) x I x constant (a) x $I_{\rm P}$

Except for $I_{\rm p}$ all terms of this equation are constant. Therefore:

$$V_{\rm H}$$
 = constant (b) x $I_{\rm P}$

The measurement signal $V_{\rm H}$ amplified to supply the user output voltage or current.



Fig. 1: Principle of the open loop transducer



Dimensions HC5FW 600-S/SP1 series (in mm)



Mechanical characteristics

- Plastic case PA 66 GF 25
- Magnetic core
 FeSi alloy
- Mass 27.5 g
- Electrical terminal coating Tin plated

Mounting recommendation

- Connector type
- Assembly torque max
 None
- Soldering profile
 See page 7

Electronic schematic



None

Remarks

- $I_{\rm P} = \left(\frac{5}{U_{\rm C}} \cdot V_{\rm out} V_{\rm O}\right) \cdot \frac{1}{G}$ with G in (V/A)
- V_{out} > V_o when I_P flows in the positive direction (see arrow on drawing).
- R1, C1: low pass filter (optional).



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Absolute ratings (not operating)

HC5FW 600-S/SP1

Parameter	Sumbol	Unit	Specification			Conditions
Farameter	Symbol	Unit	Min	Typical	Max	Conditions
Maximum supply voltage	U _c	v			8	not operating
					6.5	Exceeding this voltage may temporary reconfigure the circuit until the next power-on
Max primary current peak	\hat{I}_{P}	A			3)	
Ambient storage temperature	Ts	°C	- 40		125	
Electrostatic discharge voltage	U _{ESD}	kV			2	JESD22-A114-B class 2
Maximum admissible vibration (random)	γ	m • s-²		90		10 to 1000 Hz
RMS voltage for AC insulation test, 50 Hz, 1 min	U _d	kV			2.5	50 Hz, 1 min, IEC 60664 part1
Isolation resistance	R _{IS}	MΩ	500			
Creepage distance	d _{Cp}	mm		3.6		
Clearance	d _{ci}	mm		2.7		
Comparative traking index	CTI	V		550		
Maximum reverse current	I _R	mA	- 80		80	

Operating characteristics in nominal range ($I_{\rm PN}$)

Parameter		Unit	Specification			
	Symbol		Min	Typical	Max	Conditions
		Elec	trical Data			
Primary current, measuring range	I _{PM}	А	- 600		600	
Primary nominal DC or rms current	I _{PN}	A	- 600		600	
Supply voltage 1)	U _c	V	4.75	5.00	5.25	
Ambient operating temperature	T _A	°C	- 40		125	
Output voltage (Analog)	V _{out}	V	$V_{\text{out}} = (U_{\text{c}}/5) \cdot (V_{\text{o}} + G \cdot I_{\text{P}})$		G·I _P)	@ U _c
Sensitivity	G	mV/A		3.333		@ U _c = 5 V
Offset voltage	V _o	v		2.5		@ $T_{\rm A}$ = 25 °C, @ U _c = 5 V, Hysteresis included
Current consumption	I _c	mA		19	25	@ $U_{\rm C}$ = 5 V, - 40 °C < $T_{\rm A}$ < 125 °C
Load resistance	R	ΚΩ	10			
Capacitive loading	CL	nF		4.7	6.8	
Output internal resistance	R _{out}	Ω			10	DC to 1 KHz
		Perform	nance Data 1)			
Ratiometricity error	€ _r	%		0.5		
Sensitivity error	ε _g	%	- 1.0	± 0.5	1.0	@ T _A = 25 °C
Electrical offset voltage	V _{OE}	mV		± 2.5		@ $T_{\rm A}$ = 25 °C, @ $U_{\rm C}$ = 5 V
Magnetic offset voltage	V _{om}	mV		± 2		@ $T_{A} = 25 \text{ °C}$, @ $U_{C} = 5 \text{ V}$, after $\pm I_{P}$
Global accuracy @ 0 A	X _g	mV	- 12		12	@ $T_{\rm A}$ = 25 °C, @ $U_{\rm C}$ = 5 V, Hysteresis included
Average temperature coefficient of $V_{\rm OE}$	TCV	mV/°C	- 0.08		0.08	@ - 40 °C < T° < 125 °C
Average temperature coefficient of G	TCG _{AV}	%/°C	- 0.03		0.03	@ - 40 °C < T° < 125 °C
Linearity error	ε	% I _P	- 1		1	Of full range
Step response time to 90 % $I_{_{\rm PN}}$	t,	μs		2	6	d <i>i</i> /d <i>t</i> = 100 A/µs
Frequency bandwidth 2)	BW	kHz	40			@ - 3 dB
Phase shift	$\Delta \varphi$	°C	- 4		0	@ DC to 1 kHz
Minimum output voltage		V			0.2	@ U _c = 5 V
Maximum output voltage	V _{sz}	V	4.8			@ U _c = 5 V
Output voltage noise peak-peak	V _{no p-p}	mV			12	DC to 1 MHz

Notes:

¹⁾ The output voltage V_{out} is fully ratiometric. The offset and sensitivity are dependent on the supply voltage U_c relative to the following formula:

 $I_{\rm P} = \left(\frac{5}{U_{\rm c}} \cdot V_{\rm out} - V_{\rm o}\right) \cdot \frac{1}{G}$ with G in (V/A)

²⁾ Small signal only to avoid axcessive heating of the busbar, the magnetic core and the ASIC.

 $^{\scriptscriptstyle 3)}$ Busbar temperature must be below 150 °C.



Global Absolute Error (mV)



I _p (A)	Accuracy @ 25 °C (mV)	Accuracy @ T° Rrange (mV)
- 600	± 45	± 65
0	± 13	± 18
600	± 45	± 65

Accuracy error specified at ± 3 Sigma

Curves extracted from PV tests report.





Curves in red line represent the tolerance Curves in dotted blue line represent average + 3 sigma.



PERFORMANCES PARAMETERS DEFINITIONS

Primary current definition:



Primary current nominal (I_{pn})
 Primary current, measuring range (I_{pn})

Definition of typical, minimum and maximum values:

Minimum and maximum values for specified limiting and safety conditions have to be understood as such as values shown in "typical" graphs. On the other hand, measured values are part of a statistical distribution that can be specified by an interval with upper and lower limits and a probability for measured values to lie within this interval. Unless otherwise stated (e.g. "100 % tested"), the LEM definition for such intervals designated with "min" and "max" is that the probability for values of samples to lie in this interval is 99.73 %. For a normal (Gaussian) distribution, this corresponds to an interval between -3 sigma and +3 sigma. If "typical" values are not obviously mean or average values, those values are defined to delimit intervals with a probability of 68.27 %, corresponding to an interval between -sigma and +sigma for a normal distribution. Typical, maximal and minimal values are determined during the initial characterization of a product.

Output noise voltage:

The output voltage noise is the result of the noise floor of the Hall elements and the linear amplifier.

Magnetic offset:

The magnetic offset is the consequence of an over-current on the primary side. It's defined after an excursion of $I_{\rm PN}$

Linearity:

The maximum positive or negative discrepancy with a reference straight line $V_{\text{out}} = f(I_{\text{p}})$.

Unit: linearity (%) expressed with full scale of $I_{\rm PN}$.



Response time (delay time) t_r:

The time between the primary current signal ($I_{\rm PN}$) and the output signal reach at 90 % of its final value.



Sensitivity:

The Transducer's sensitivity *G* is the slope of the straight line $V_{out} = f(I_p)$, it must establish the relation: $V_{out}(I_p) = U_c/5 (G \cdot I_p + V_o)$.

Offset with temperature:

The error of the offset in the operating temperature is the variation of the offset in the temperature considered with the initial offset at 25 $^{\circ}$ C.

The offset variation $I_{\rm ot}$ is a maximum variation the offset in the temperature range:

 $I_{\text{OT}} = I_{\text{OF}} \max - I_{\text{OF}} \min$

The Offset drift $\textit{TCI}_{\rm OEAV}$ is the $I_{\rm OT}$ value divided by the temperature range.

Sensitivity with temperature:

The error of the sensitivity in the operating temperature is the relative variation of sensitivity with the temperature considered with the initial offset at 25 $^{\circ}$ C.

The sensitivity variation G_{τ} is the maximum variation (in ppm or %) of the sensitivity in the temperature range:

 G_{τ} = (Sensitivity max - Sensitivity min) / Sensitivity at 25 °C.

The sensitivity drift TCG_{AV} is the G_T value divided by the temperature range. Deeper and detailed info available is our LEM technical sales offices (www.lem.com).

Offset voltage @ $I_{\rm P}$ = 0 A:

The offset voltage is the output voltage when the primary current is null. The ideal value of $V_{\rm o}$ is $U_{\rm c}/2$ at $U_{\rm c}$ = 5 V. So, the difference of $V_{\rm o}$ - $U_{\rm c}/2$ is called the total offset voltage error. This offset error can be attributed to the electrical offset (due to the resolution of the ASIC quiescent voltage trimming), the magnetic offset, the thermal drift and the thermal hysteresis. Deeper and detailed info available is our LEM technical sales offices (www.lem.com).



Environmental test specifications:

Refer to LEM GROUP test plan laboratory CO.11.11.515.0 with "Tracking_Test Plan_Auto" sheet.

Name	Standard					
THERMAL FATIGUE						
Ageing 85 °C / 85 % <i>HR</i> / 1000 h Thermal cycle test - 40 °C / 125 °C / 1000 h Thermal shocks - 40 °C / 125 °C / 1000 h High temperature storage at 125 °C / 1000 h Low temperature storage at - 50 °C / 1000 h	IEC 60068-2-78 (2001) IEC 60068-2-14 test Nb (01.2009) IEC 60068-2-14 test Na (01.2009) IEC 60068-2-14 test Na (01.2009) IEC 60068-2-2 (07.2007) IEC 60068-2-1 (03.2007)					
MECHANICAL FATIGUE						
Shocks test (50 m·s² x 10 x 3 axis) Vibration test (random 10 - 2000 Hz / 9.723 g)	IEC 60068-2-27 test Ea (2008)					
ELECTRICAL TESTS						
Phase delay Output noise di/dt (100 A/µs) dv/dt (2 kVA/µs to 2 kV) Withstand voltage (2500 V rms - 50 Hz / 1 min) Insulation resistance (500 Vdc / 1 min)	 98.20.00.575.0 98.20.00.545.0 98.20.00.545.0 ISO 16750-2 (2012)					
EMC TESTS						
Radiated Emissions: Absorber Lined Shielded Enclosure (ALSE) Radiated Immunity: Bulk Current Injection (BCI) Radiated Immunity: Anechoic chamber Resistance to Electrostatic Discharge Voltage	IEC CISPR25 ISO 11452-1 & -4 ISO 11452-1 & -2 ISO 10605 (2001)					



Soldering recommendations:

- 1 Iron Soldering plated-through holes device
- Mass pin (E1 to E4 see on drawing page 2): 200 W / 370 °C Iron temperature / 7 mm flat W200 Weller
- ASIC terminals (1,2,3,4 see on drawing page 2): 80 W / 410 °C Iron temperaure / 0.8 mm diameter STTC125 Metcal
- 2 Wave soldering plated-through holes device

LEM recommends to use the following equipment/parameters for the soldering of the HC5FW family in order to be compliant with the IPC A-610 (less than 75 % land coverage):

- Machine VITRONICS SOLTEC 6622 in combi wave mode
- Flux SLS 65
- Sn96 lead free solder (SAC 305)
- Temperature profile as below
- PCB 2143-00 thickness: 1.6 mm mass pin E1 to E4: hole Ø 2 Asic pin: hole Ø 1.



- 3 SMD soldering by pin in paste STH (SMD through hole)
- Must be validated by user
- ASIC MSL 1 level.